

**Notice of References Cited**

Application/Control No.

10/699,706

Applicant(s)/Patent Under  
Reexamination  
TAKAHASHI ET AL.

Examiner

Alexander O Williams

Art Unit

2826

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,777,387	07-1998	Yamashita et al.	257/737
	B	US-5,786,239	07-1998	Ohsawa et al.	438/123
	C	US-6,194,778	02-2001	Ohsawa et al.	257/668
	D	US-5,668,405	09-1997	Yamashita, Chikara	257/668
	E	US-5,886,399	03-1999	Ohsawa et al.	257/668
	F	US-5,474,957	12-1995	Urushima, Michitaka	29/827
	G	US-2002/0063331 A1	05-2002	HONDA, HIROKAZU	257/737
	H	US-6,104,091	08-2000	Ito et al.	257/738
	I	US-5,998,241	12-1999	Niwa, Kouichirou	438/122
	J	US-2002/0096781 A1	07-2002	Toyosawa, Kenji	257/777
	K	US-6,303,219 B1	10-2001	Sawamura et al.	428/343
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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